MT3040

N-Channel Low $Qg^{\mathbb{R}}$ MOSFET 45V, 100A, 4.5m Ω

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conven tional swit ching PWM controllers. It has been optimized for low gate charge, low $r_{\text{DS}(\text{ON})}$ and fast switching speed.

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Applications



Features

r_{DS(ON)}

•

· Low gate charge

DC/DC converters.UPS.Inverter





High power and current handling capability

r_{DS(ON)} = 4.5mΩ, V_{GS} = 10V, I_D = 10A

r_{DS(ON)} = 6.0mΩ, V_{GS} = 4.5V, I_D = 10A

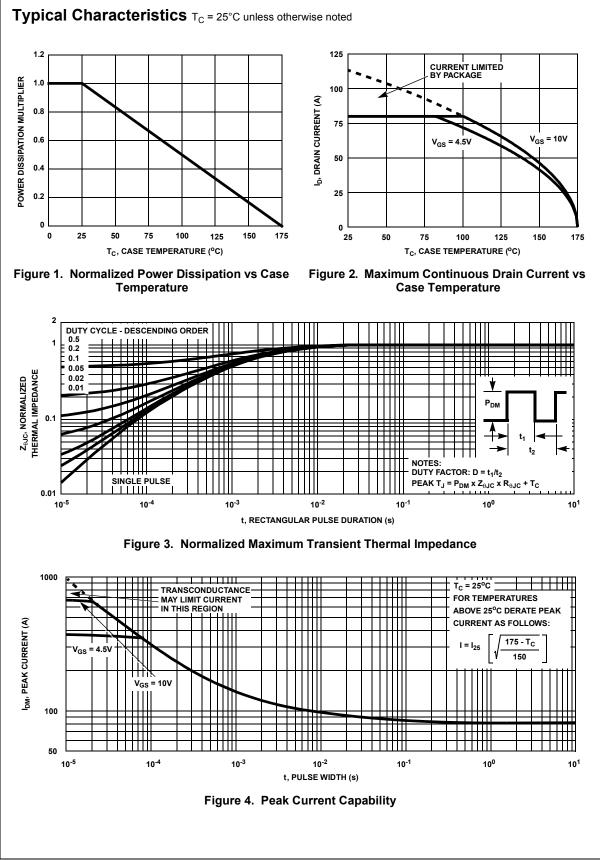
· High performance trench technology for extremely low

MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

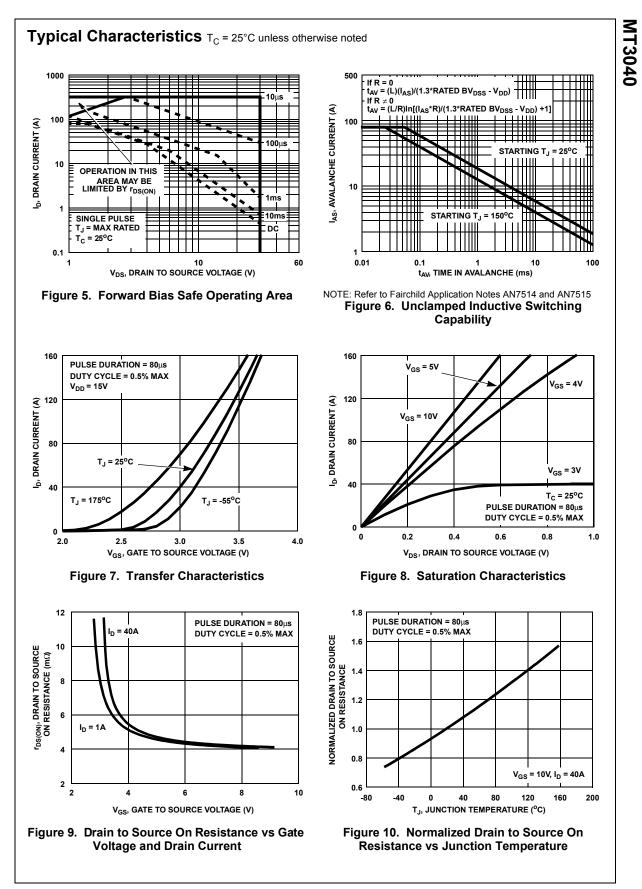
	Parameter Ratings		Units			
Drain to Sou	rce Voltage			45	V	
Gate to Sour	o Source Voltage			±20	V	
Drain Current						
Continuous ($T_c = 25^{\circ}C$, $V_{GS} = 10V$) (Note 1)				100	A	
Continuous (Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 4.5V$) (Note 1)				А	
Continuous (А	
Pulsed		Figure 4	А			
Single Pulse	Single Pulse Avalanche Energy (Note 2)				mJ	
Power dissipation				110	W	
Derate above	e 25ºC	0.73	W/ºC			
Operating ar	nd Storage Temperat	-55 to 175	°C			
		Case TO-220		1.42	°C/W	
Thermal Res	sistance Junction to /	64	°C/W			
e Marking	and Orderin	ng Informatio	DN Reel Size	Tape Width	Quantity	
		rackage	11001 0120		50 units	
	Gate to Sour Drain Curren Continuous (Continuous (Continuous (Pulsed Single Pulse Power dissip Derate above Operating ar I Charact e Thermal Res Thermal Res	Drain to Source Voltage Gate to Source Voltage Drain Current Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 10$ Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 4$. Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} =$ Pulsed Single Pulse Avalanche Energy (I Power dissipation Derate above $25^{\circ}C$ Operating and Storage Temperat Al Characteristics Thermal Resistance Junction to A e Marking and Orderin	Drain to Source Voltage Gate to Source Voltage Drain Current Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 10V$) (Note 1) Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 4.5V$) (Note 1) Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$, with $R_{\theta JA} = 62$ Pulsed Single Pulse Avalanche Energy (Note 2) Power dissipation Derate above $25^{\circ}C$ Operating and Storage Temperature Il Characteristics Thermal Resistance Junction to Case TO-220 Thermal Resistance Junction to Ambient TO-220 (N e Marking and Ordering Informatic	Drain to Source Voltage Gate to Source Voltage Drain Current Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 10V$) (Note 1) Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 4.5V$) (Note 1) Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$, with $R_{\theta JA} = 62^{\circ}C/W$) Pulsed Single Pulse Avalanche Energy (Note 2) Power dissipation Derate above $25^{\circ}C$ Operating and Storage Temperature Il Characteristics Thermal Resistance Junction to Case TO-220 Thermal Resistance Junction to Ambient TO-220 (Note 3) e Marking and Ordering Information	Drain to Source Voltage45Gate to Source Voltage ± 20 Drain Current100Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 10V$) (Note 1)100Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 4.5V$) (Note 1)85Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$, with $R_{\theta JA} = 62^{\circ}C/W$)15PulsedFigure 4Single Pulse Avalanche Energy (Note 2)105Power dissipation110Derate above $25^{\circ}C$ 0.73Operating and Storage Temperature-55 to 175I Characteristics1.42Thermal Resistance Junction to Case TO-220 (Note 3)64e Marking and Ordering Information	

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Symbol	Parameter	Test Conditions		Min	Тур	Max	Unit
Off Chara	acteristics						
B _{VDSS}	Drain to Source Breakdown Voltage	I _D = 250μA, V _{GS} =	= 0V	45	-	-	V
	-	V _{DS} = 24V		-	-	1	
IDSS	Zero Gate Voltage Drain Current	50	T _C = 150°C	- 0°C	-	250	μA
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±20V		-	-	±100	nA
On Chara	octeristics						
V _{GS(TH)}	Gate to Source Threshold Voltage	V _{GS} = V _{DS} , I _D = 2	1.4	1.6	2.0	V	
00(11)		$I_{\rm D}$ = 10A, $V_{\rm GS}$ = 10V		-	0.0045	0.0048	Ω
	Drain to Course On Desistance	$I_{\rm D}$ = 10A, $V_{\rm GS}$ = 4.5V		-	0.006	0.007	
r _{DS(ON)}	Drain to Source On Resistance	I _D = 10A, V _{GS} = 1 T _J = 175 ^o C	-	0.009	0.01		
Dynamic	Characteristics	5		I	1		
	Input Capacitance			_	2013	-	pF
C _{OSS}	Output Capacitance	──V _{DS} = 15V, V _{GS} = 0V, f = 1MHz		-	452	-	pF
C _{RSS}	Reverse Transfer Capacitance			-	184	-	pF
R _G	Gate Resistance	V _{GS} = 0.5V, f = 1N	ИНz	-	1.9	-	Ω
Q _{g(TOT)}	Total Gate Charge at 10V	$V_{GS} = 0V \text{ to } 10V$		-	56	72	nC
Q _{g(5)}	Total Gate Charge at 5V	$\frac{V_{GS} = 0V \text{ to } 5V}{V_{GS} = 0V \text{ to } 1V} V_{DD} = 15V$ $I_D = 40A$	-	35	39	nC	
Q _{g(TH)}	Threshold Gate Charge		-	3.4	4.7	nC	
Q _{gs}	Gate to Source Gate Charge		-	9.7	-	nC	
Q _{gs2}	Gate Charge Threshold to Plateau		l _g = 1.0mA	-	6.5	-	nC
Q _{gd}	Gate to Drain "Miller" Charge	_		-	11	-	nC
	g Characteristics (V _{GS} = 10V)						
t _{ON}	Turn-On Time			-	-	202	ns
t _{d(ON)}	Turn-On Delay Time	V_{DD} = 15V, I _D = 40A V_{GS} = 4.5V, R _{GS} = 4.7Ω		-	12		ns
t _r	Rise Time			-	120	-	ns
t _{d(OFF)}	Turn-Off Delay Time			-	42	-	ns
t _f	Fall Time			-	30	-	ns
t _{OFF}	Turn-Off Time			-	-	112	ns
	urce Diode Characteristics						
				-	-	1.25	V
V _{SD}	Source to Drain Diode Voltage	I _{SD} = 20A		-	-	1.0	V
t _{rr}	Reverse Recovery Time	I _{SD} = 40A, dI _{SD} /dt = 100A/μs		-	-	32	ns
	Reverse Recovered Charge	I _{SD} = 40A, dI _{SD} /dt = 100A/μs		-	-	18	nC

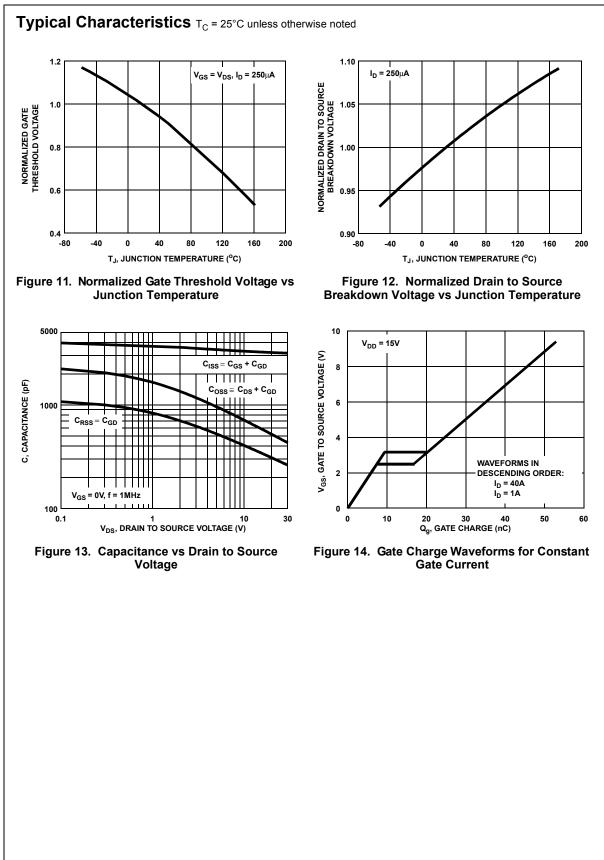


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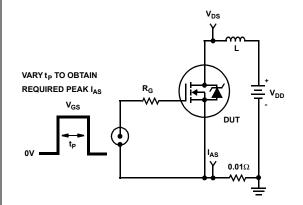
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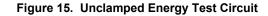


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Test Circuits and Waveforms



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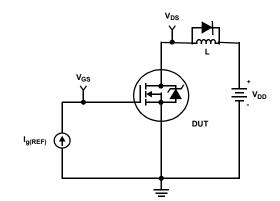


Figure 17. Gate Charge Test Circuit

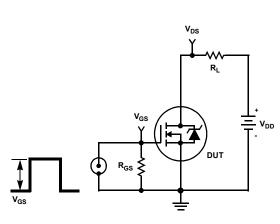


Figure 19. Switching Time Test Circuit

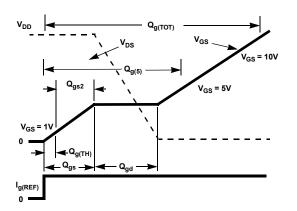
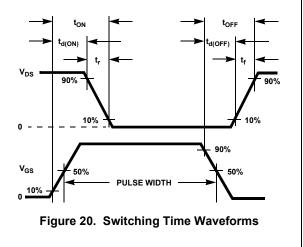
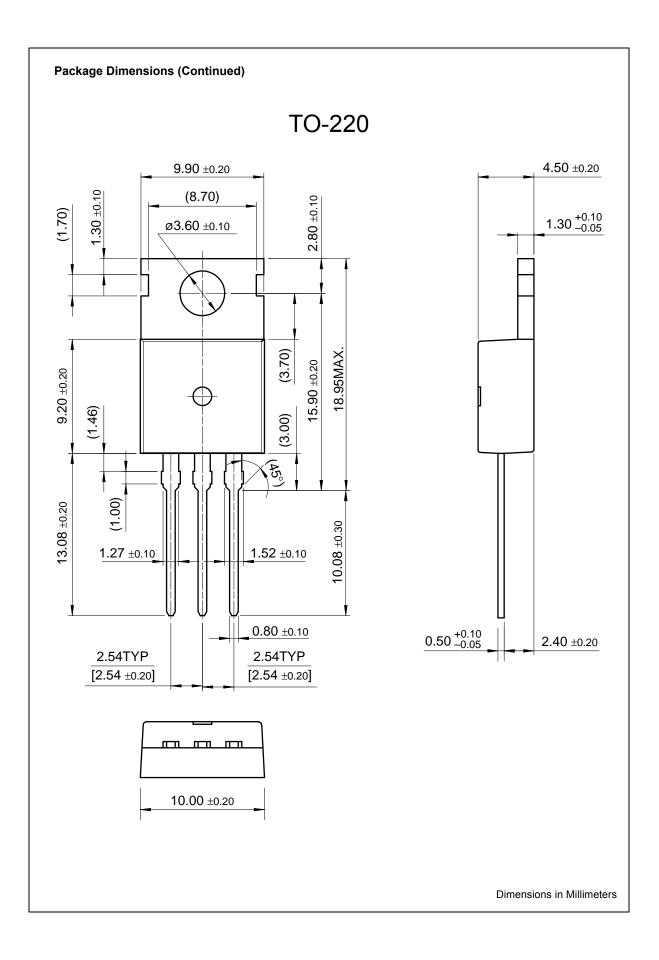


Figure 18. Gate Charge Waveforms







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